

Notice of References Cited	Application/Control No. 09/842,948		Applicant(s)/Patent Under Reexamination PETRY ET AL.	
	Examiner PHILIP WANG		Art Unit 2191	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,813,621	11-2004	Taylor et al.	707/102
	C	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	V	Gedeon et al., "Applying Machine Vision In Electrical Component Manufacturing", Electrical Electronics Insulation Conference and Electrical Manufacturing & Coil Winding Conference, 1993. Proceedings., Chicago '93 EEIC/ICWA Exposition 4-7 Oct. 1993 Page(s):737 - 749
	W	Kassim et al., "Automatic IC orientation checks", Spring-Verlag 2000, April, Machine Vision and Application, pp. 107-112
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.